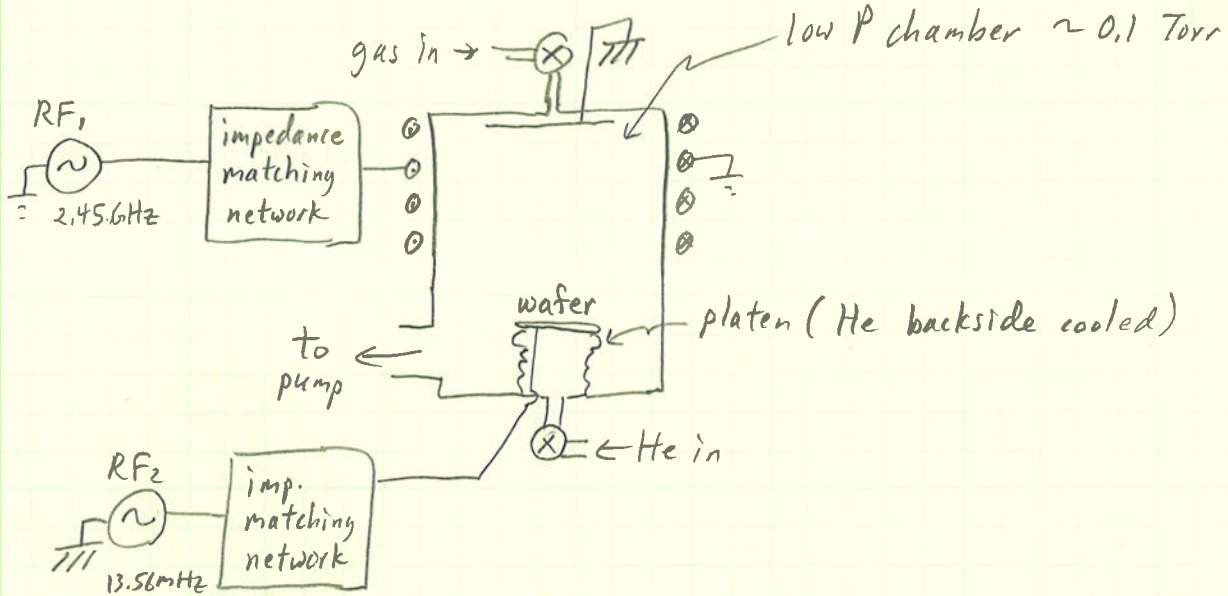


1. Reactive Ion Etching (RIE)

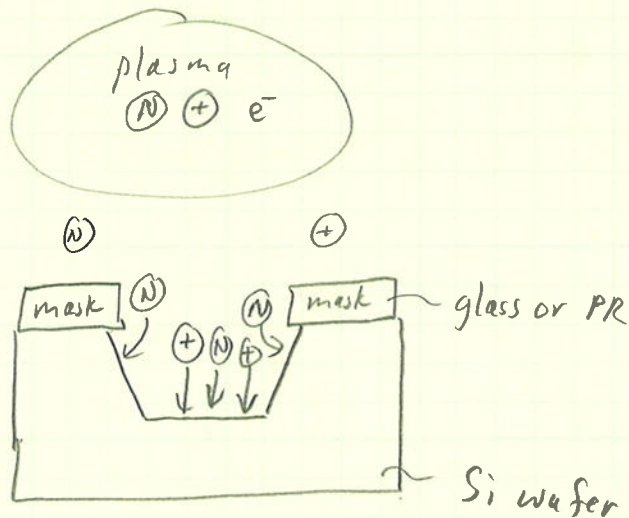
→ combines chemical etching using reactive neutrals with sputtering to produce better anisotropic etching



wafer is held on the platen either mechanically or electrostatically

RF₁ → produce plasma

RF₂ → provide an effective large negative bias on the platen to accelerate positive ions to the wafer for sputtering



(N) → chemically convert Si to a gas

(+) → sputter Si from exposed horizontal surfaces ((N) react w/ sputtered Si too)

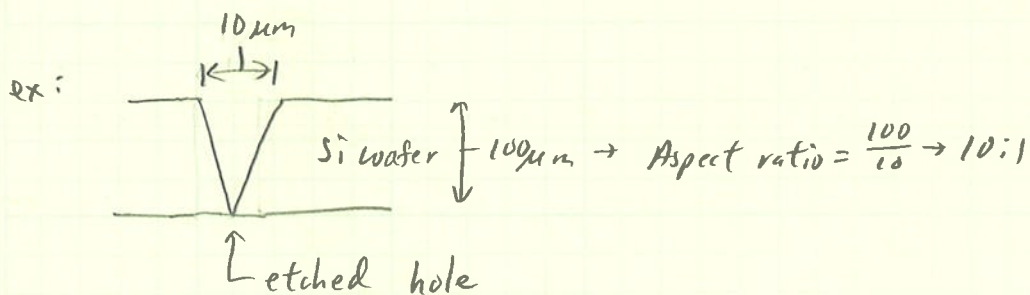
Sputtering heats up the wafer \rightarrow He backside cooling is used

\rightarrow sputtering results in a more anisotropic etch than plasma etching alone with reactive neutrals

\rightarrow Aspect Ratio - a measure of the anisotropy of the dry etch

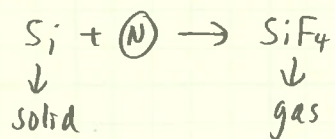
\rightarrow a ratio of vertical etch to the horizontal etch

\rightarrow the limit of what a process or machine can achieve \rightarrow is a metric for that process or machine



RIE gas chemistries: various chemistries can be used

\rightarrow typical used gases: SF_6 , CF_4 , NF_3



RIE \rightarrow aspect ratios of 10-15 can be achieved

2. Deep Reactive Ion Etching (DRIE)

RZE based on the Bosch Process

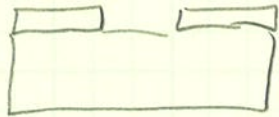
→ uses a sequential alternating process of etching and passivation

Etch step → SF_6 / Ar plasma (300-1200W 2.45GHz RF power) with
a -5V to -30V platen bias (2-10W 13.56MHz RF power)

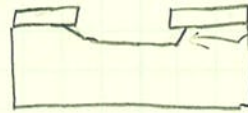
↓
accelerates positive ions $\sim 90^\circ$ toward
substrate → sputtering

→ short etch step

start

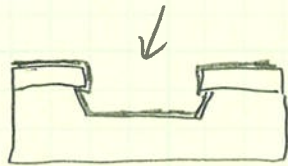


stop

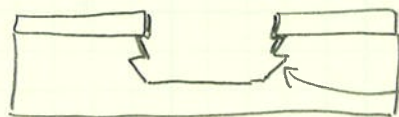


slight undercut

Passivation step → all surfaces coated with $\sim 50\text{nm}$ thick polymer coating (\sim Teflon) → $\text{C}_4\text{F}_8 + \text{SF}_6 \rightarrow \text{CF}_2$



next etch step → sputtering ions quickly removes passivation coating from horizontal surfaces (so Si etching continues) but not from vertical surfaces (prevents lateral Si etching)

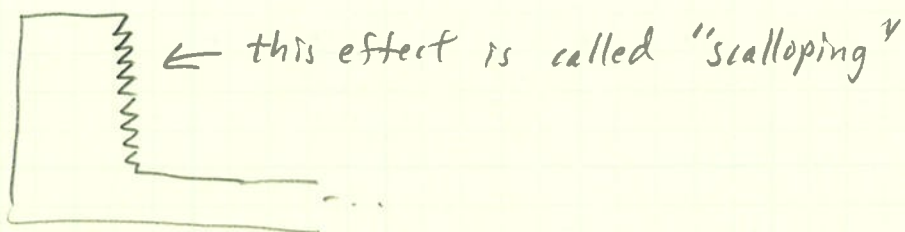


more undercutting

next passivation step, etc...

Result → Aspect ratios as high as 30 can be achieved.
 → vertical etched sidewalls are not smooth

ex:



Ex: STS ASE (Advanced Silicon Etcher)

→ etch rate : 1.5 to 3.0 $\mu\text{m}/\text{min}$

aspect ratio : up to 30 (10 is typical)

selectivity to SiO_2 : 120 to 200:1

mask : PR or SiO_2 typically used

→ etches (100), (110) or (111) \sim equally

How can scalloping be removed?

→ dip in an alkaline etchant : KOH or TMAH

→ thermal oxidation followed by SiO_2 removal (BOE or HF)